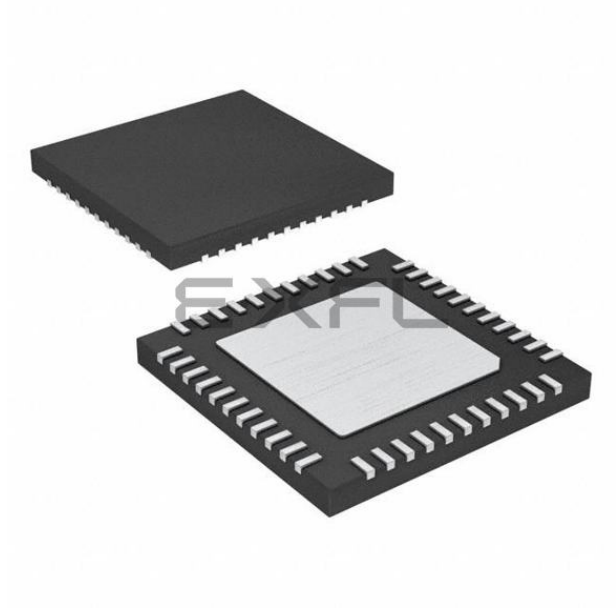

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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I²C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	34
Program Memory Size	16KB (8K x 16)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 12x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	44-VFQFN Exposed Pad
Supplier Device Package	44-VQFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega16a4u-mhr

11. Power Management and Sleep Modes

11.1 Features

- Power management for adjusting power consumption and functions
- Five sleep modes
  - Idle
  - Power down
  - Power save
  - Standby
  - Extended standby
- Power reduction register to disable clock and turn off unused peripherals in active and idle modes

11.2 Overview

Various sleep modes and clock gating are provided in order to tailor power consumption to application requirements. This enables the Atmel AVR XMEGA microcontroller to stop unused modules to save power.

All sleep modes are available and can be entered from active mode. In active mode, the CPU is executing application code. When the device enters sleep mode, program execution is stopped and interrupts or a reset is used to wake the device again. The application code decides which sleep mode to enter and when. Interrupts from enabled peripherals and all enabled reset sources can restore the microcontroller from sleep to active mode.

In addition, power reduction registers provide a method to stop the clock to individual peripherals from software. When this is done, the current state of the peripheral is frozen, and there is no power consumption from that peripheral. This reduces the power consumption in active mode and idle sleep modes and enables much more fine-tuned power management than sleep modes alone.

11.3 Sleep Modes

Sleep modes are used to shut down modules and clock domains in the microcontroller in order to save power. XMEGA microcontrollers have five different sleep modes tuned to match the typical functional stages during application execution. A dedicated sleep instruction (SLEEP) is available to enter sleep mode. Interrupts are used to wake the device from sleep, and the available interrupt wake-up sources are dependent on the configured sleep mode. When an enabled interrupt occurs, the device will wake up and execute the interrupt service routine before continuing normal program execution from the first instruction after the SLEEP instruction. If other, higher priority interrupts are pending when the wake-up occurs, their interrupt service routines will be executed according to their priority before the interrupt service routine for the wake-up interrupt is executed. After wake-up, the CPU is halted for four cycles before execution starts.

The content of the register file, SRAM and registers are kept during sleep. If a reset occurs during sleep, the device will reset, start up, and execute from the reset vector.

11.3.1 Idle Mode

In idle mode the CPU and nonvolatile memory are stopped (note that any ongoing programming will be completed), but all peripherals, including the interrupt controller, event system and DMA controller are kept running. Any enabled interrupt will wake the device.

11.3.2 Power-down Mode

In power-down mode, all clocks, including the real-time counter clock source, are stopped. This allows operation only of asynchronous modules that do not require a running clock. The only interrupts that can wake up the MCU are the two-wire interface address match interrupt, asynchronous port interrupts, and the USB resume interrupt.

13. WDT – Watchdog Timer

13.1 Features

- Issues a device reset if the timer is not reset before its timeout period
- Asynchronous operation from dedicated oscillator
- 1kHz output of the 32kHz ultra low power oscillator
- 11 selectable timeout periods, from 8ms to 8s
- Two operation modes:
  - Normal mode
  - Window mode
- Configuration lock to prevent unwanted changes

13.2 Overview

The watchdog timer (WDT) is a system function for monitoring correct program operation. It makes it possible to recover from error situations such as runaway or deadlocked code. The WDT is a timer, configured to a predefined timeout period, and is constantly running when enabled. If the WDT is not reset within the timeout period, it will issue a microcontroller reset. The WDT is reset by executing the WDR (watchdog timer reset) instruction from the application code.

The window mode makes it possible to define a time slot or window inside the total timeout period during which WDT must be reset. If the WDT is reset outside this window, either too early or too late, a system reset will be issued. Compared to the normal mode, this can also catch situations where a code error causes constant WDR execution.

The WDT will run in active mode and all sleep modes, if enabled. It is asynchronous, runs from a CPU-independent clock source, and will continue to operate to issue a system reset even if the main clocks fail.

The configuration change protection mechanism ensures that the WDT settings cannot be changed by accident. For increased safety, a fuse for locking the WDT settings is also available.

28. ADC – 12-bit Analog to Digital Converter

28.1 Features

- One Analog to Digital Converter (ADC)
- 12-bit resolution
- Up to two million samples per second
  - Two inputs can be sampled simultaneously using ADC and 1x gain stage
  - Four inputs can be sampled within 1.5µs
  - Down to 2.5µs conversion time with 8-bit resolution
  - Down to 3.5µs conversion time with 12-bit resolution
- Differential and single-ended input
  - Up to 12 single-ended inputs
  - 12x4 differential inputs without gain
  - 8x4 differential inputs with gain
- Built-in differential gain stage
  - 1/2x, 1x, 2x, 4x, 8x, 16x, 32x, and 64x gain options
- Single, continuous and scan conversion options
- Four internal inputs
  - Internal temperature sensor
  - DAC output
  - AV_{CC} voltage divided by 10
  - 1.1V bandgap voltage
- Four conversion channels with individual input control and result registers
  - Enable four parallel configurations and results
- Internal and external reference options
- Compare function for accurate monitoring of user defined thresholds
- Optional event triggered conversion for accurate timing
- Optional DMA transfer of conversion results
- Optional interrupt/event on compare result

28.2 Overview

The ADC converts analog signals to digital values. The ADC has 12-bit resolution and is capable of converting up to two million samples per second (msps). The input selection is flexible, and both single-ended and differential measurements can be done. For differential measurements, an optional gain stage is available to increase the dynamic range. In addition, several internal signal inputs are available. The ADC can provide both signed and unsigned results.

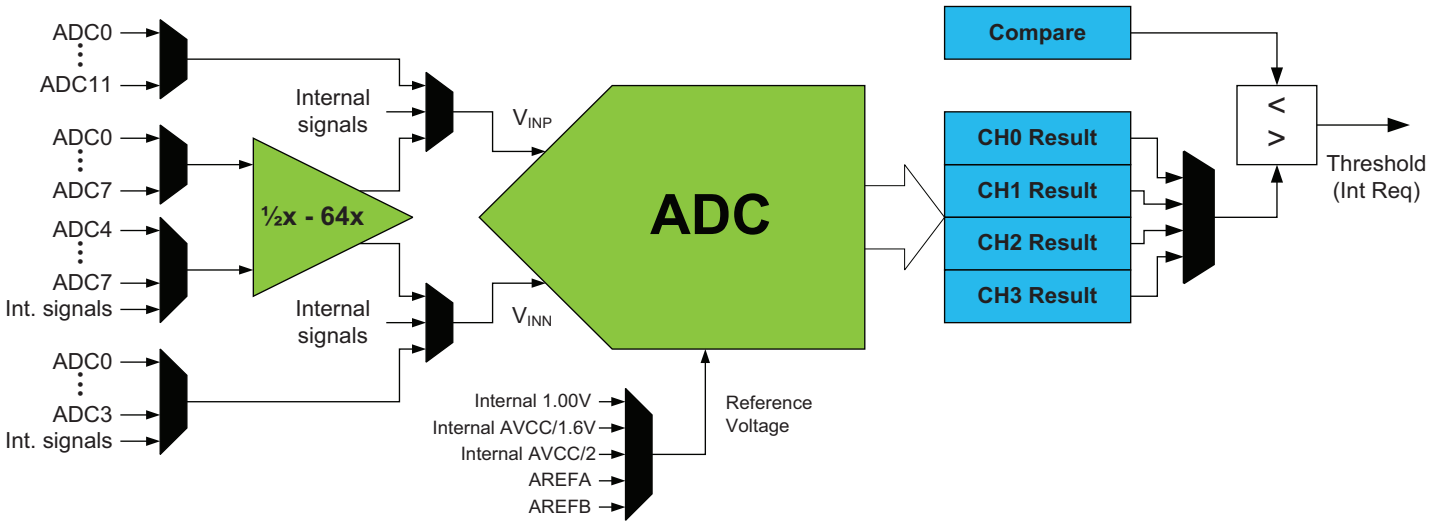
This is a pipelined ADC that consists of several consecutive stages. The pipelined design allows a high sample rate at a low system clock frequency. It also means that a new input can be sampled and a new ADC conversion started while other ADC conversions are still ongoing. This removes dependencies between sample rate and propagation delay.

The ADC has four conversion channels (0-3) with individual input selection, result registers, and conversion start control. The ADC can then keep and use four parallel configurations and results, and this will ease use for applications with high data throughput or for multiple modules using the ADC independently. It is possible to use DMA to move ADC results directly to memory or peripherals when conversions are done.

Both internal and external reference voltages can be used. An integrated temperature sensor is available for use with the ADC. The output from the DAC, $AV_{CC}/10$ and the bandgap voltage can also be measured by the ADC.

The ADC has a compare function for accurate monitoring of user defined thresholds with minimum software intervention required.

Figure 28-1. ADC overview.



Two inputs can be sampled simultaneously as both the ADC and the gain stage include sample and hold circuits, and the gain stage has 1x gain setting. Four inputs can be sampled within 1.5µs without any intervention by the application.

The ADC may be configured for 8- or 12-bit result, reducing the minimum conversion time (propagation delay) from 3.5µs for 12-bit to 2.5µs for 8-bit result.

ADC conversion results are provided left- or right adjusted with optional ‘1’ or ‘0’ padding. This eases calculation when the result is represented as a signed integer (signed 16-bit number).

PORTA has one ADC. Notation of this peripheral is ADCA.

29. DAC – 12-bit Digital to Analog Converter

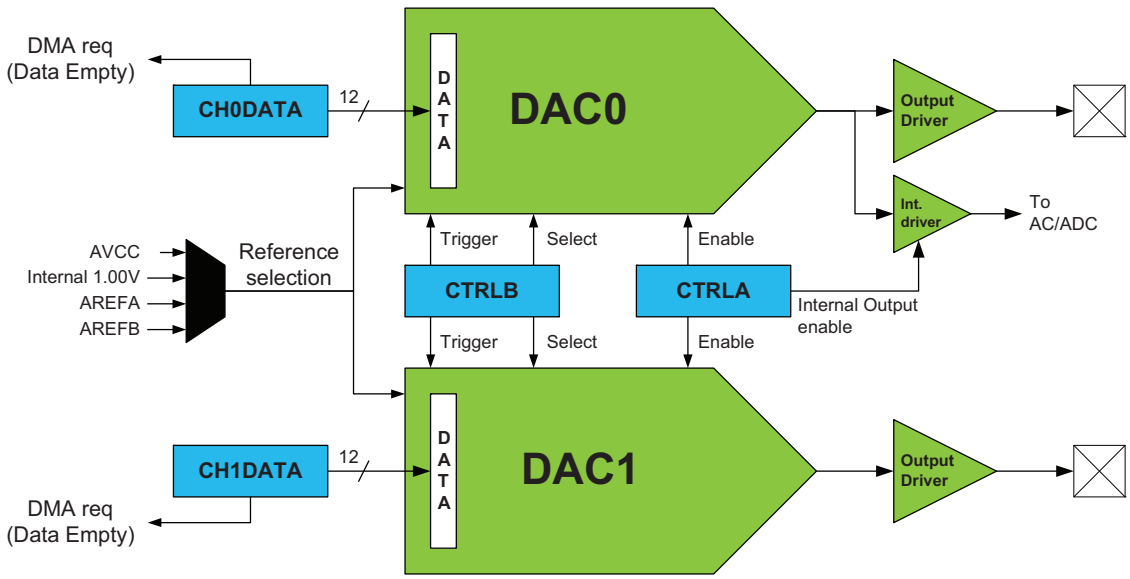
29.1 Features

- One Digital to Analog Converter (DAC)
- 12-bit resolution
- Two independent, continuous-drive output channels
- Up to one million samples per second conversion rate per DAC channel
- Built-in calibration that removes:
  - Offset error
  - Gain error
- Multiple conversion trigger sources
  - On new available data
  - Events from the event system
- High drive capabilities and support for
  - Resistive loads
  - Capacitive loads
  - Combined resistive and capacitive loads
- Internal and external reference options
- DAC output available as input to analog comparator and ADC
- Low-power mode, with reduced drive strength
- Optional DMA transfer of data

29.2 Overview

The digital-to-analog converter (DAC) converts digital values to voltages. The DAC has two channels, each with 12-bit resolution, and is capable of converting up to one million samples per second (msps) on each channel. The built-in calibration system can remove offset and gain error when loaded with calibration values from software.

Figure 29-1. DAC overview.



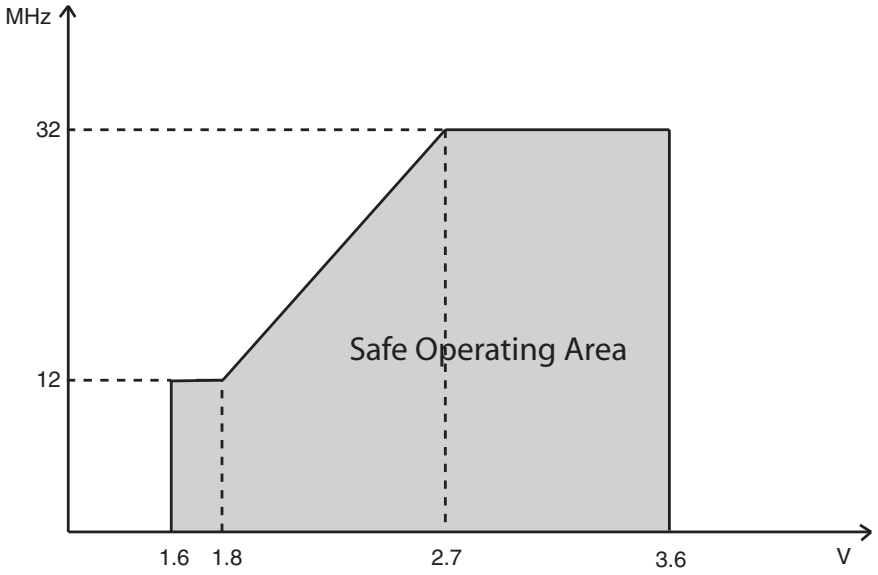
36.1.3 Current consumption

Table 36-4. Current consumption for Active mode and sleep modes.

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
I_{CC}	Active power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		40		µA
			V_{CC} = 3.0V		80		
		1MHz, Ext. Clk	V_{CC} = 1.8V		230		
			V_{CC} = 3.0V		480		
		2MHz, Ext. Clk	V_{CC} = 1.8V		430	600	
			V_{CC} = 3.0V		0.9	1.4	mA
		32MHz, Ext. Clk			9.6	12	
	Idle power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		2.4		µA
			V_{CC} = 3.0V		3.9		
		1MHz, Ext. Clk	V_{CC} = 1.8V		62		
			V_{CC} = 3.0V		118		
		2MHz, Ext. Clk	V_{CC} = 1.8V		125	225	
			V_{CC} = 3.0V		240	350	
		32MHz, Ext. Clk			3.8	5.5	mA
	Power-down power consumption	T = 25°C	V_{CC} = 3.0V		0.1	1.0	µA
		T = 85°C			1.2	4.5	
		T = 105°C			3.5	6.0	
		WDT and Sampled BOD enabled, T = 25°C	V_{CC} = 3.0V		1.3	3.0	
		WDT and Sampled BOD enabled, T = 85°C			2.4	6.0	
		WDT and Sampled BOD enabled, T = 105°C			4.5	8.0	
	Power-save power consumption (2)	RTC from ULP clock, WDT and sampled BOD enabled, T = 25°C	V_{CC} = 1.8V		1.2		µA
			V_{CC} = 3.0V		1.3		
		RTC from 1.024kHz low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.6	2.0	
			V_{CC} = 3.0V		0.7	2.0	
		RTC from low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.8	3.0	
			V_{CC} = 3.0V		1.0	3.0	
	Reset power consumption	Current through $\overline{\text{RESET}}$ pin substracted	V_{CC} = 3.0V		320		µA

Notes:
1. All Power Reduction Registers set.
2. Maximum limits are based on characterization, and not tested in production.

Figure 36-8. Maximum Frequency vs. V_{CC}.



36.2.10 Brownout Detection Characteristics

Table 36-49. Brownout detection characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{BOT}	BOD level 0 falling V_{CC}		1.60	1.62	1.72	V
	BOD level 1 falling V_{CC}			1.8		
	BOD level 2 falling V_{CC}			2.0		
	BOD level 3 falling V_{CC}			2.2		
	BOD level 4 falling V_{CC}			2.4		
	BOD level 5 falling V_{CC}			2.6		
	BOD level 6 falling V_{CC}			2.8		
	BOD level 7 falling V_{CC}			3.0		
t_{BOD}	Detection time	Continuous mode		0.4		µs
		Sampled mode		1000		
V_{HYST}	Hysteresis			1.2		%

36.2.11 External Reset Characteristics

Table 36-50. External reset characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{EXT}	Minimum reset pulse width			95	1000	ns
V_{RST}	Reset threshold voltage (V_{IH})	V_{CC} = 2.7 - 3.6V		0.60*V_{CC}		V
		V_{CC} = 1.6 - 2.7V		0.60*V_{CC}		
	Reset threshold voltage (V_{IL})	V_{CC} = 2.7 - 3.6V		0.50*V_{CC}		
		V_{CC} = 1.6 - 2.7V		0.40*V_{CC}		
R_{RST}	Reset pin Pull-up Resistor			25		kΩ

36.2.12 Power-on Reset Characteristics

Table 36-51. Power-on reset characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{POT-} (1)	POR threshold voltage falling V_{CC}	V_{CC} falls faster than 1V/ms	0.4	1.0		V
		V_{CC} falls at 1V/ms or slower	0.8	1.0		
V_{POT+}	POR threshold voltage rising V_{CC}			1.3	1.59	V

Note: 1. V_{POT-} values are only valid when BOD is disabled. When BOD is enabled V_{POT-} = V_{POT+}.

Table 36-74. Accuracy characteristics.

Symbol	Parameter	Condition [2]		Min.	Typ.	Max.	Units
RES	Resolution	Programmable to 8 or 12 bit		8	12	12	Bits
INL [1]	Integral non-linearity	500ksps	V_{CC}-1.0V < V_{REF}< V_{CC}-0.6V		±1.2	±2	lsb
			All V_{REF}		±1.5	±3	
		2000ksps	V_{CC}-1.0V < V_{REF}< V_{CC}-0.6V		±1.0	±2	
			All V_{REF}		±1.5	±3	
DNL [1]	Differential non-linearity	guaranteed monotonic			<±0.8	<±1	lsb
	Offset error				-1		mV
		Temperature drift			<0.01		mV/K
		Operating voltage drift			<0.6		mV/V
	Gain error	Differential mode	External reference		-1		mV
			AV_{CC}/1.6		10		
			AV_{CC}/2.0		8		
			Bandgap		±5		
		Temperature drift			<0.02		mV/K
		Operating voltage drift			<0.5		mV/V
	Noise	Differential mode, shorted input 2msps, V_{CC} = 3.6V, Clk_{PER} = 16MHz			0.4		mV rms

Notes:
1. Maximum numbers are based on characterisation and not tested in production, and valid for 5% to 95% input voltage range.
2. Unless otherwise noted all linearity, offset and gain error numbers are valid under the condition that external V_{REF} is used.

Table 36-75. Gain stage characteristics.

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
R_{in}	Input resistance	Switched in normal mode			4.0		kΩ
C_{sample}	Input capacitance	Switched in normal mode			4.4		pF
	Signal range	Gain stage output		0		V_{CC}- 0.6	V
	Propagation delay	ADC conversion rate			1.0		Clk_{ADC} cycles
	Sample rate	Same as ADC		100		1000	kHz
INL [1]	Integral non-linearity	500ksps	All gain settings		±1.5	±4.0	lsb
	Gain error	1x gain, normal mode			-0.8		%
		8x gain, normal mode			-2.5		
		64x gain, normal mode			-3.5		

36.3.14.4 32kHz Internal ULP Oscillator characteristics

Table 36-89. 32kHz internal ULP oscillator characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Factory calibrated frequency			32		kHz
	Factory calibrated accuracy	T = 85°C, V_{CC} = 3.0V	-12		12	%
	Accuracy		-30		30	%

36.3.14.5 Internal Phase Locked Loop (PLL) characteristics

Table 36-90. Internal PLL characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
f_{IN}	Input frequency	Output frequency must be within f_{OUT}	0.4		64	MHz
f_{OUT}	Output frequency (1)	V_{CC}= 1.6 - 1.8V	20		48	MHz
		V_{CC}= 2.7 - 3.6V	20		128	
	Start-up time			25		µs
	Re-lock time			25		µs

Note: 1. The maximum output frequency vs. supply voltage is linear between 1.8V and 2.7V, and can never be higher than four times the maximum CPU frequency.

36.3.14.6 External clock characteristics

Figure 36-17. External clock drive waveform

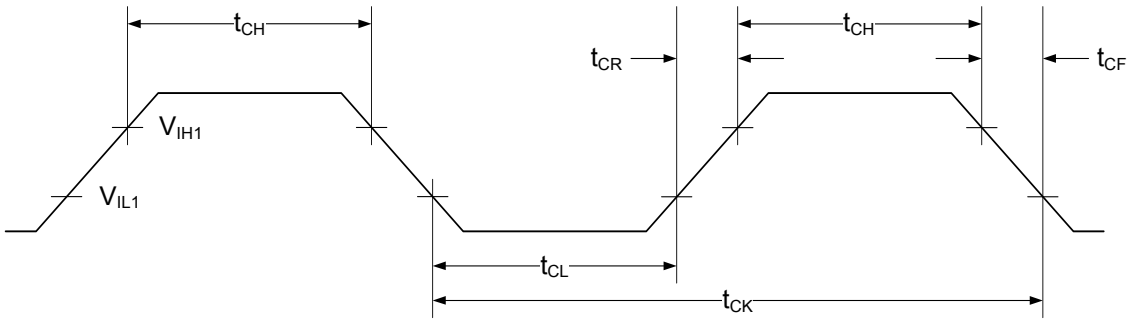


Table 36-91. External clock used as system clock without prescaling.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$1/t_{CK}$	Clock Frequency (1)	V_{CC} = 1.6 - 1.8V	0		12	MHz
		V_{CC} = 2.7 - 3.6V	0		32	
t_{CK}	Clock Period	V_{CC} = 1.6 - 1.8V	83.3			ns
		V_{CC} = 2.7 - 3.6V	31.5			
t_{CH}	Clock High Time	V_{CC} = 1.6 - 1.8V	30.0			ns
		V_{CC} = 2.7 - 3.6V	12.5			

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$t_{HD;DAT}$	Data hold time	$f_{SCL} \leq 100kHz$	0		3.45	µs
		$f_{SCL} > 100kHz$	0		0.9	
$t_{SU;DAT}$	Data setup time	$f_{SCL} \leq 100kHz$	250			ns
		$f_{SCL} > 100kHz$	100			
$t_{SU;STO}$	Setup time for STOP condition	$f_{SCL} \leq 100kHz$	4.0			µs
		$f_{SCL} > 100kHz$	0.6			
t_{BUF}	Bus free time between a STOP and START condition	$f_{SCL} \leq 100kHz$	4.7			µs
		$f_{SCL} > 100kHz$	1.3			

Notes:
1. Required only for $f_{SCL} > 100kHz$.
2. C_b = Capacitance of one bus line in pF.
3. f_{PER} = Peripheral clock frequency.

36.4.5 I/O Pin Characteristics

The I/O pins comply with the JEDEC LVTTL and LVCMOS specification and the high- and low level input and output voltage limits reflect or exceed this specification.

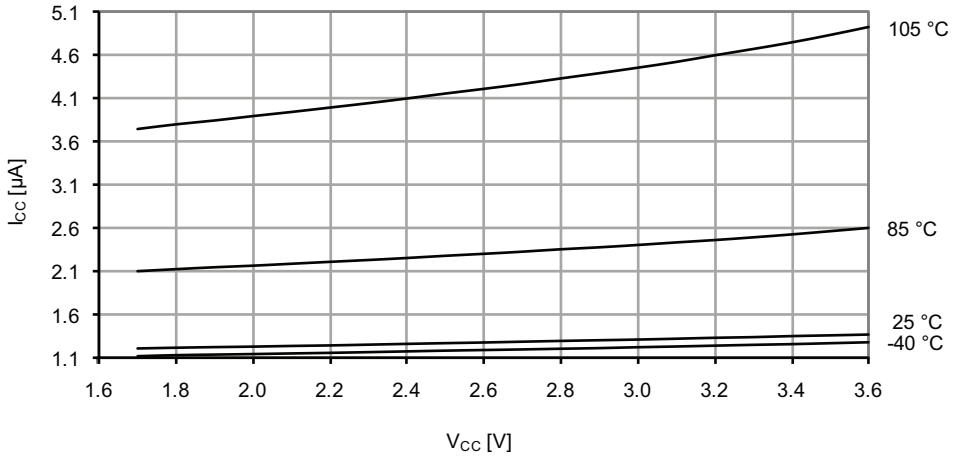
Table 36-103.I/O pin characteristics.

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
I_{OH} (1)/ I_{OL} (2)	I/O pin source/sink current			-20		20	mA
V_{IH}	High level input voltage	V_{CC} = 2.7 - 3.6V		2.0		V_{CC}+0.3	V
		V_{CC} = 2.0 - 2.7V		0.7*V_{CC}		V_{CC}+0.3	
		V_{CC} = 1.6 - 2.0V		0.8*V_{CC}		V_{CC}+0.3	
V_{IL}	Low level input voltage	V_{CC} = 2.7- 3.6V		-0.3		0.8	V
		V_{CC} = 2.0 - 2.7V		-0.3		0.3*V_{CC}	
		V_{CC} = 1.6 - 2.0V		-0.3		0.2*V_{CC}	
V_{OH}	High level output voltage	V_{CC} = 3.0 - 3.6V	I_{OH} = -2mA	2.4	0.94*V_{CC}		V
		V_{CC} = 2.3 - 2.7V	I_{OH} = -1mA	2.0	0.96*V_{CC}		
			I_{OH} = -2mA	1.7	0.92*V_{CC}		
		V_{CC} = 3.3V	I_{OH} = -8mA	2.6	2.9		
		V_{CC} = 3.0V	I_{OH} = -6mA	2.1	2.6		
		V_{CC} = 1.8V	I_{OH} = -2mA	1.4	1.6		
V_{OL}	Low level output voltage	V_{CC} = 3.0 - 3.6V	I_{OL} = 2mA		0.05	0.4	V
		V_{CC} = 2.3 - 2.7V	I_{OL} = 1mA		0.03	0.4	
			I_{OL} = 2mA		0.06	0.7	
		V_{CC} = 3.3V	I_{OL} = 15mA		0.4	0.76	
		V_{CC} = 3.0V	I_{OL} = 10mA		0.3	0.64	
		V_{CC} = 1.8V	I_{OL} = 5mA		0.2	0.46	
I_{IN}	Input leakage current	T = 25°C			<0.01	0.1	µA
R_P	Pull/buss keeper resistor				24		kΩ
t_r	Rise time	No load			4.0		ns
			slew rate limitation		7.0		

Notes:
1. The sum of all I_{OH} for PORTA and PORTB must not exceed 100mA.
   The sum of all I_{OH} for PORTC must not exceed 200mA.
   The sum of all I_{OH} for PORTD and pins PE[0-1] on PORTE must not exceed 200mA.
   The sum of all I_{OH} for PE[2-3] on PORTE, PORTR and PDI must not exceed 100mA.
2. The sum of all I_{OL} for PORTA and PORTB must not exceed 100mA.
   The sum of all I_{OL} for PORTC must not exceed 200mA.
   The sum of all I_{OL} for PORTD and pins PE[0-1] on PORTE must not exceed 200mA.
   The sum of all I_{OL} for PE[2-3] on PORTE, PORTR and PDI must not exceed 100mA.

Figure 37-17. Power-down mode supply current vs. V_{CC}.

Watchdog and sampled BOD enabled.



37.1.1.4 Power-save mode supply current

Figure 37-18. Power-save mode supply current vs.V_{CC}.

Real Time Counter enabled and running from 1.024kHz output of 32.768kHz TOSC.

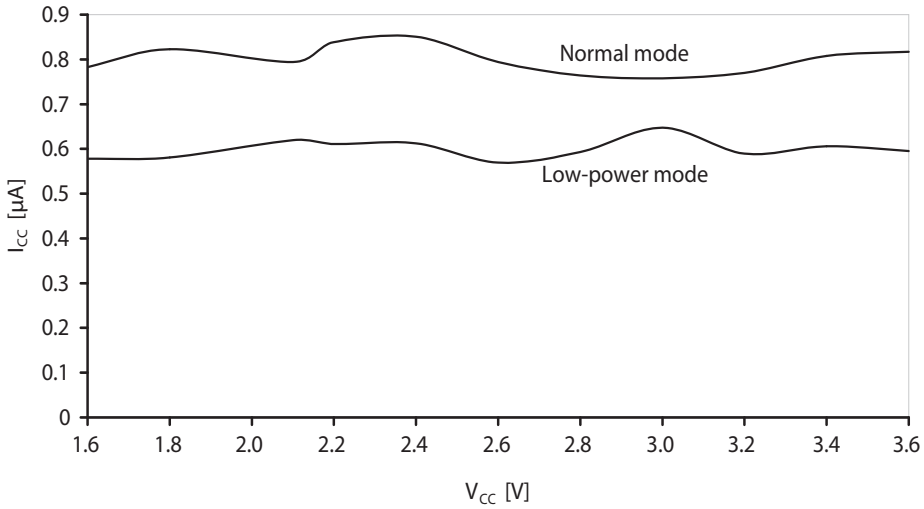
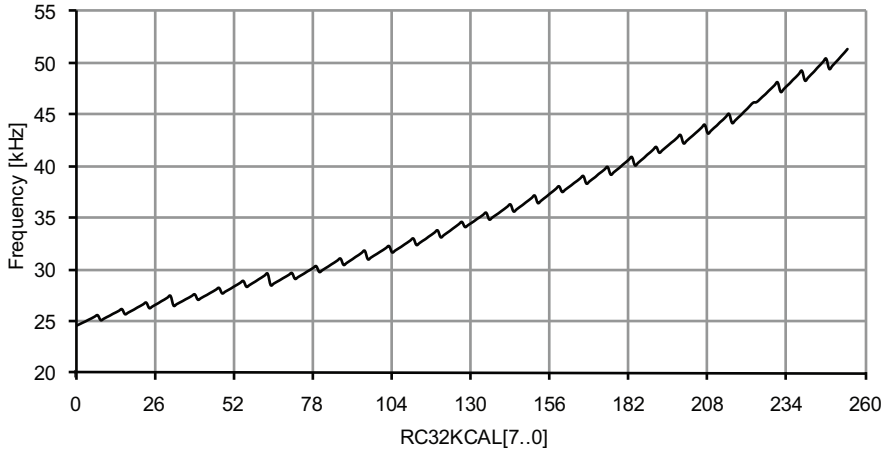


Figure 37-72. 32.768kHz internal oscillator frequency vs. calibration value.

V_{CC} = 3.0V, T = 25°C.



37.1.10.3 2MHz Internal Oscillator

Figure 37-73. 2MHz internal oscillator frequency vs. temperature.

DFLL disabled.

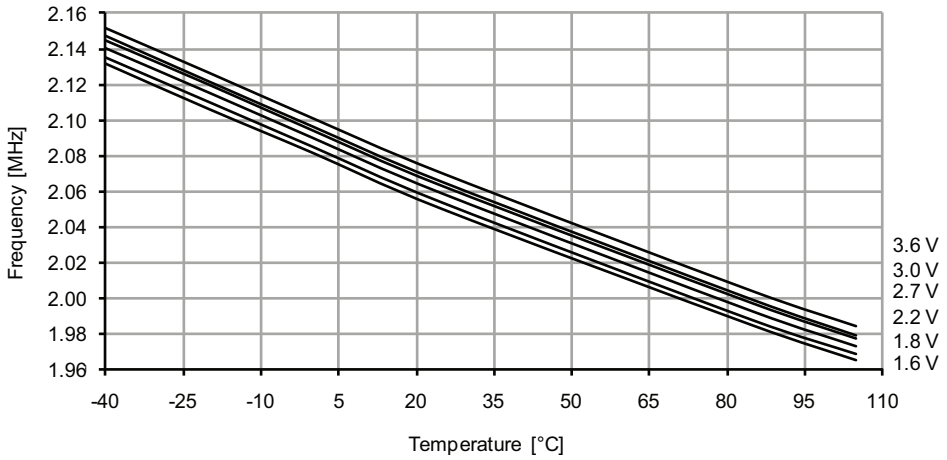


Figure 37-95. Idle mode supply current vs. V_{CC}.

f_{SYS} = 1MHz external clock.

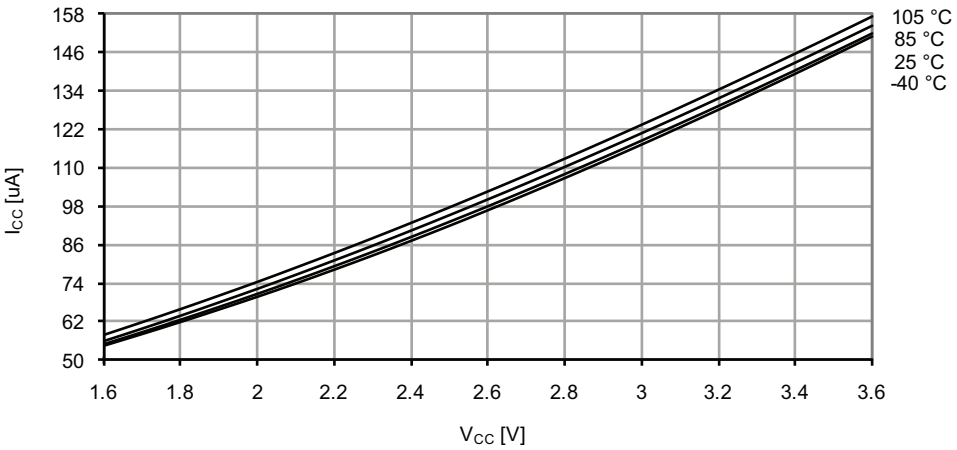


Figure 37-96. Idle mode supply current vs. V_{CC}.

f_{SYS} = 2MHz internal oscillator.

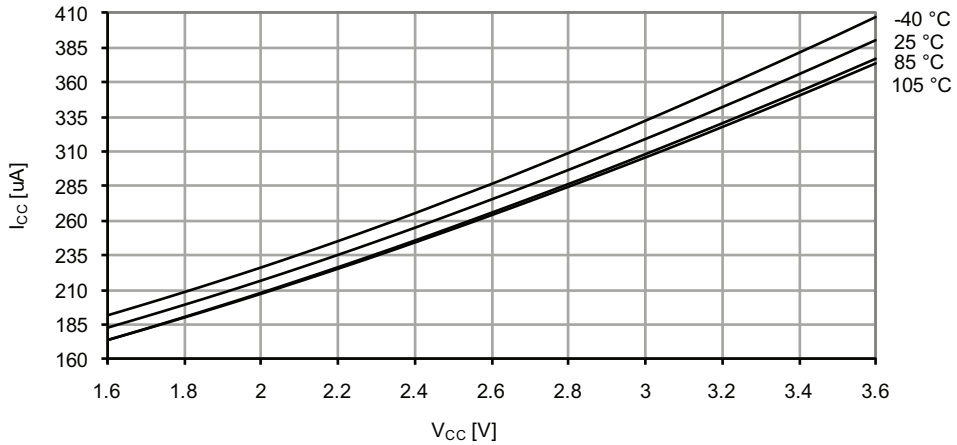


Figure 37-173. Active mode supply current vs. V_{CC}.

f_{SYS} = 2MHz internal oscillator.

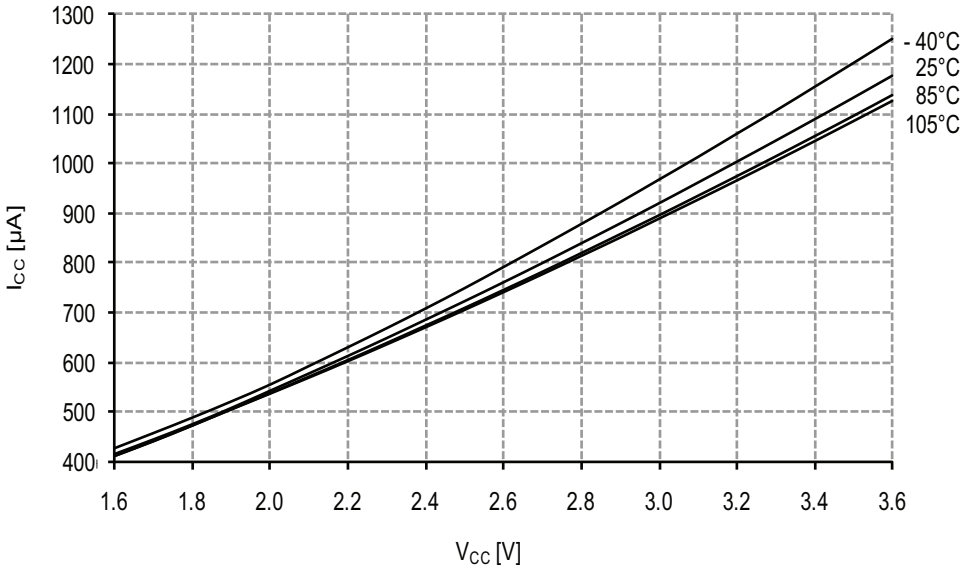


Figure 37-174. Active mode supply current vs. V_{CC}.

f_{SYS} = 32MHz internal oscillator prescaled to 8MHz.

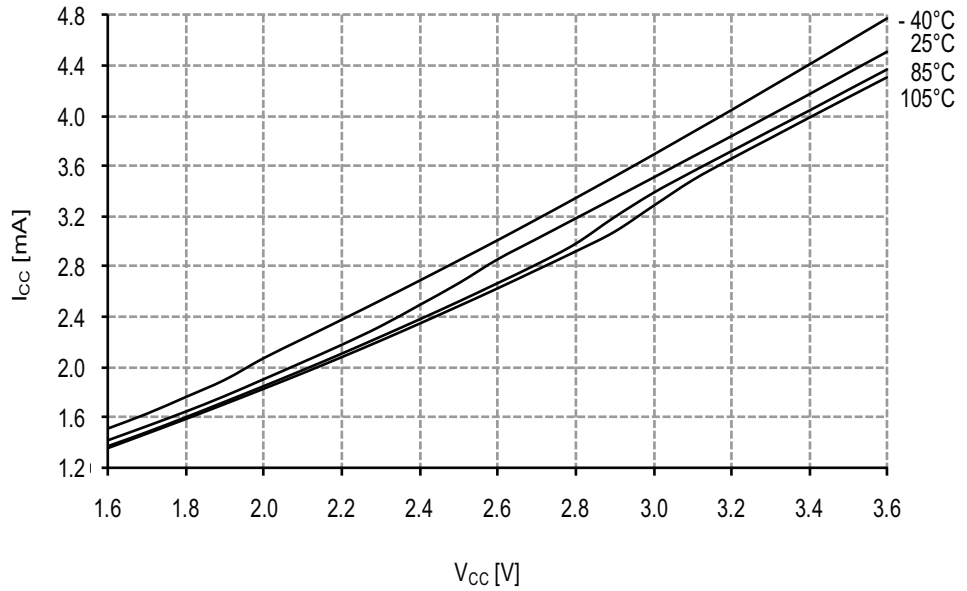
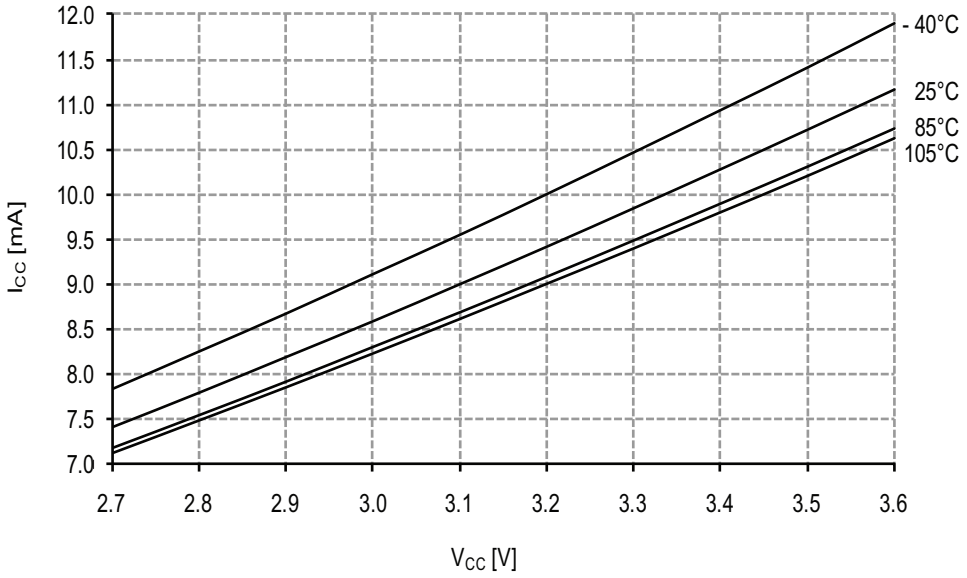


Figure 37-175. Active mode supply current vs. V_{CC}.

f_{SYS} = 32MHz internal oscillator.



37.3.1.2 Idle mode supply current

Figure 37-176. Idle mode supply current vs. frequency.

f_{SYS} = 0 - 1MHz external clock, T = 25°C.

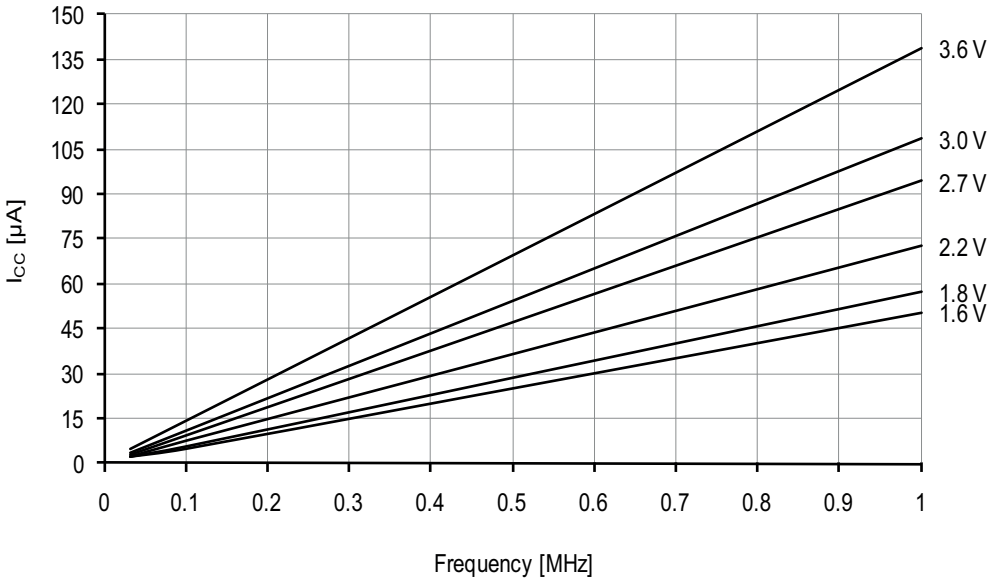


Figure 37-205. INL error vs. sample rate.

T = 25°C, V_{CC} = 2.7V, V_{REF} = 1.0V external.

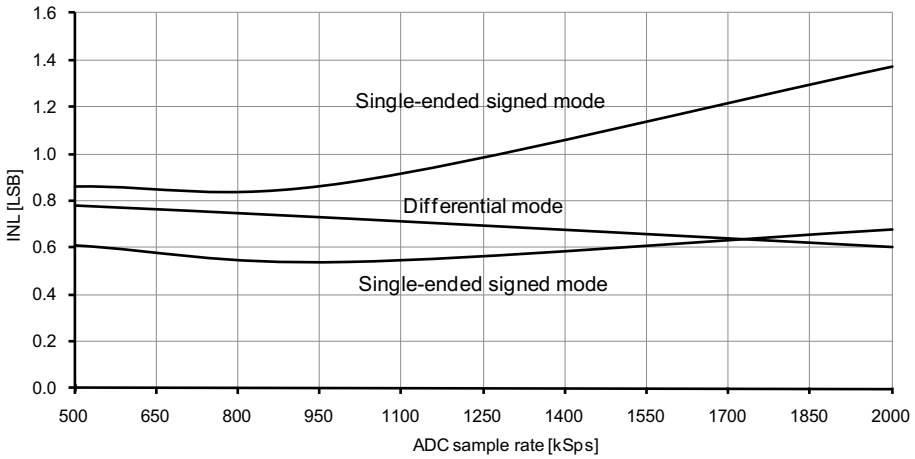


Figure 37-206. INL error vs. input code

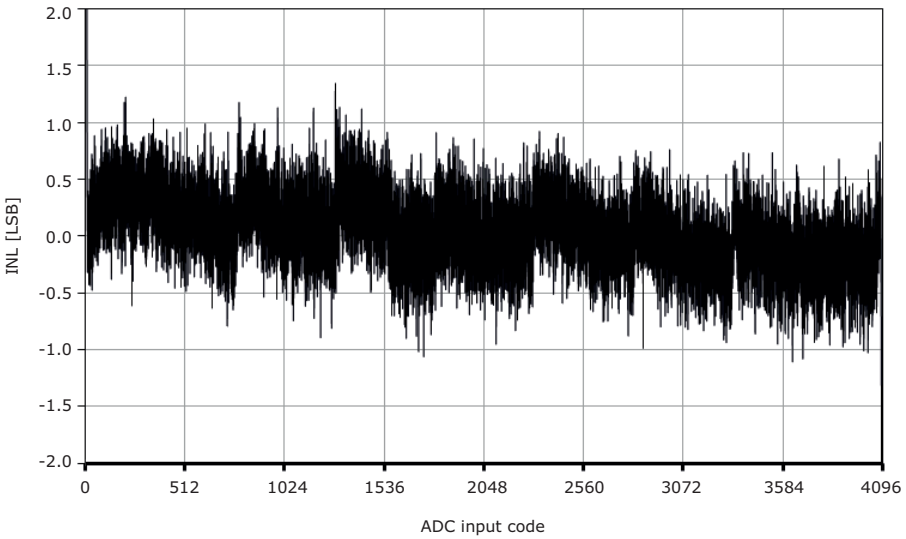


Figure 37-233. Reset pin pull-up resistor current vs. reset pin voltage.

V_{CC} = 3.3V.

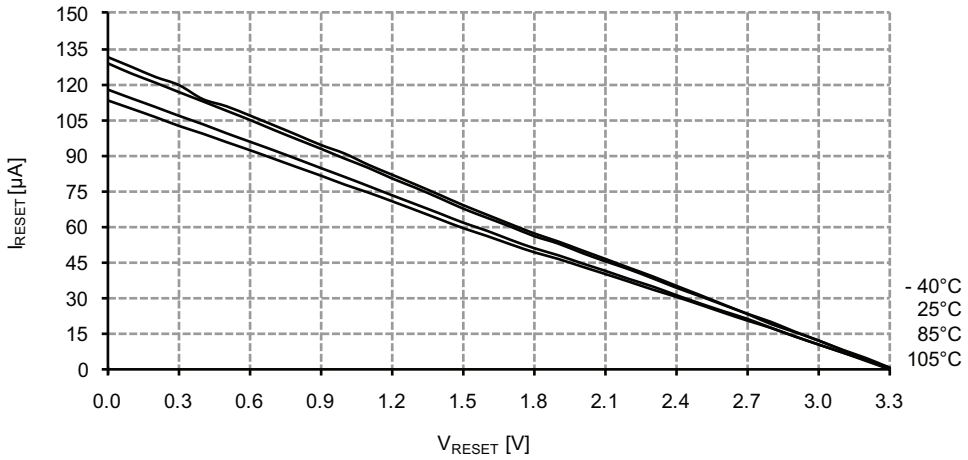


Figure 37-234. Reset pin input threshold voltage vs. V_{CC}.

V_{IH} - Reset pin read as "1".

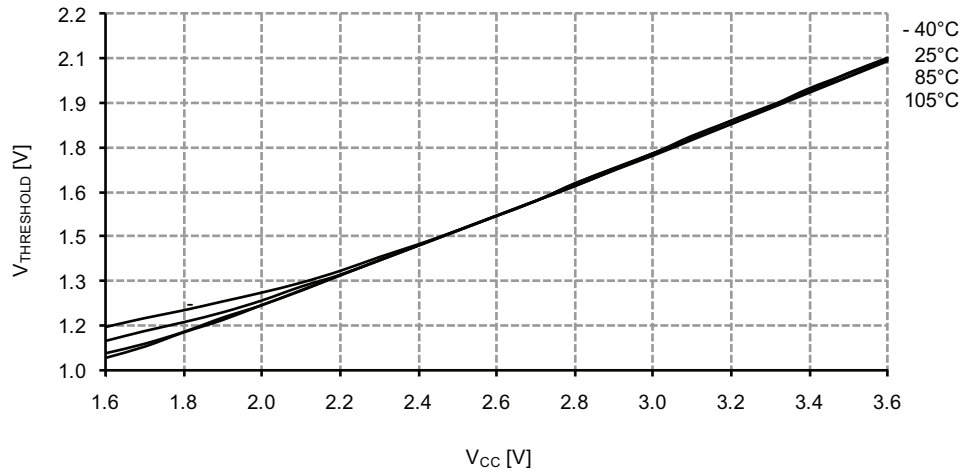


Figure 37-291. DNL error vs. external V_{REF}

T = 25°C, V_{CC} = 3.6V, external reference

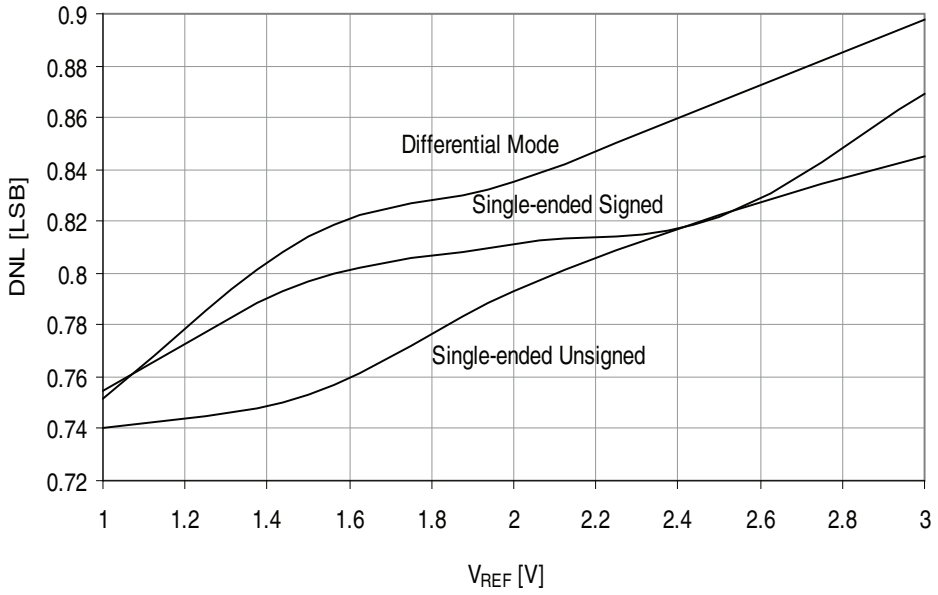


Figure 37-292. DNL error vs. sample rate

T = 25°C, V_{CC} = 3.6V, V_{REF} = 3.0V external